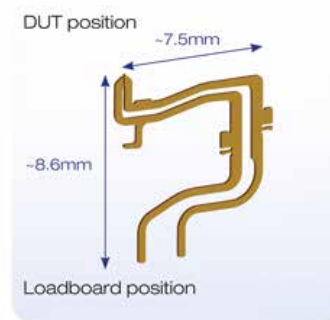


cCompact Contactor

Multisite Testing of Analog and Smart Power Devices requiring Kelvin Test



Innovative High Density Socket Architecture for High Parallelism Applications



Automotive / Power



Mobility



Precision Analog / Sensors



High End Digital



RF

High Productivity

- Extremely long cleaning interval
- Easy single pin replacement
- Very long pin life due to use of Denmark Alloy

Key Features

- Reduced site to site pitch concept enables high parallel test for power applications on Strip test and Pick & Place handler platforms
- Outstanding CRES stability
- Smallest pitch: 0.40 mm
- Static connection to load board
- Current carrying capability 3.0 A

- Temperature range -60°C to +175 °C
- Integrated socket air-distribution

- Contact resistance 40 mΩ
- High current carrying capacity

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Specifications

Electronic Specifications

- CRES average
 - 40 mOhm / Thebe Plating
 - 80 mOhm / Gold Plating
- Current Carrying Capability ⁽¹⁾
 - 3.0 A / Thebe Plating
 - 2.5 A / Gold Plating
- Self Inductance ⁽²⁾
 - 6.5 nH
- Capacitance GND ⁽²⁾
 - 0.80 pF
- Insertion loss S₂₁ ⁽²⁾
 - -1 dB @ 1.5 GHz

Mechanical Specifications

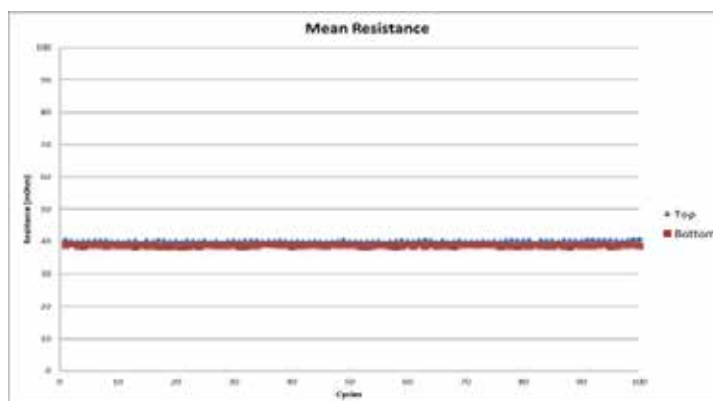
- Compressed Contact Height
 - 7.90 mm

⁽¹⁾ PER ISMI # 09075021A-TR

⁽²⁾ Results for 0.5 mm pitch

- Contact Force
 - 50 grams for 100% Sn lead plating
 - 35 grams for NiPd lead plating
- Minimum Pitch
 - 0.40 mm
- Contact Compliance
 - 0.30 mm
- Temperature Range
 - -60°C to +175°C
- Pin Material
 - Proprietary Denmark Alloy
- Pin Plating
 - Thebe
 - Gold
- Housing Material
 - Torlon 5030
- Pin Lifetime
 - 1,000,000 (typical)
- Cleaning Interval
 - > 100,000 (typical)

Contact Resistance on Gold



All specifications are subject to change without notification and are for reference only. Use contactor drawing to design interface hardware. For detailed performance specifications, please contact Cohu.